

MME65R280Q

650V 0.28Ω N-channel MOSFET

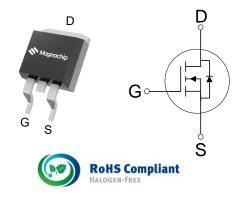
Description

MME65R280Q is power MOSFET using Magnachip's advanced super junction technology that can realize very low on-resistance and gate charge. It will provide much high efficiency by using optimized charge coupling technology. These user friendly devices give an advantage of low EMI to designers as well as low switching loss.

■ Key Parameters

Parameter	Value	Unit
V_{DS} @ $T_{j, max}$	700	V
R _{DS(on), max}	0.28	Ω
$V_{GS(th),\ typ}$	3	V
I_D	13.8	Α
Q _{g, typ}	27.8	nC

■ Package & Internal Circuit



Features

- Low power loss by high speed switching and low on-resistance
- 100% avalanche tested
- Green package Pb-free plating, Halogen-free

Applications

- PFC power supply stages
- Switching applications
- Adapter

Ordering Information

Order Code	Marking	Temp. Range	Package	Packing	RoHS Status
MME65R280QRH	65R280Q	-55 ~ 150°C	TO-263	Reel	compliant



■ Absolute Maximum Rating (T_c=25°C unless otherwise specified)

Parameter	Symbol	Rating	Unit	Note
Drain – Source voltage	V _{DSS}	650	V	
Gate – Source voltage	V _{GSS}	±30	V	
Continuous dusin summent		13.8	А	T _C = 25°C
Continuous drain current	l _D	8.7	Α	T _C = 100°C
Pulsed drain current ⁽¹⁾	I _{DM}	41.4	Α	
Power dissipation	P _D	104.2	W	
Single - pulse avalanche energy	E _{AS}	290	mJ	
MOSFET dv/dt ruggedness	dv/dt	50	V/ns	
Diode dv/dt ruggedness ⁽²⁾	dv/dt	15	V/ns	
Storage temperature	T _{stg}	-55 ~150	°C	
Maximum operating junction temperature	Tj	150	°C	

¹⁾ Id limited by maximum junction temperature

■ Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal resistance, junction-case max	R _{thjc}	1.2	°C/W
Thermal resistance, junction-ambient max ⁽³⁾	R _{thja}	62	°C/W

³⁾ Device mounted on minimal footprint of PCB.

²⁾ Pulse width tp limited by Tj,max



■ Static Characteristics (T_c=25°C unless otherwise specified)

Parameter	Symbol	Min.	Тур.	Max.	Unit	Test Condition
Drain – source breakdown voltage	V _{(BR)DSS}	650	-	-	V	V _{GS} = 0V, I _D = 250uA
Gate threshold voltage	V _{GS(th)}	2	3	4	٧	$V_{DS} = V_{GS}$, $I_D = 250$ uA
Zero gate voltage drain current	I _{DSS}	-	-	1	uA	V _{DS} = 650V, V _{GS} = 0V
Gate leakage current	I _{GSS}	-	-	100	nA	$V_{GS} = \pm 30V, V_{DS} = 0V$
Drain-source on state resistance	R _{DS(ON)}	-	0.25	0.28	Ω	V _{GS} = 10V, I _D = 4.4A

■ Dynamic Characteristics (T_c=25°C unless otherwise specified)

Parameter	Symbol	Min.	Тур.	Max.	Unit	Test Condition
Input capacitance	C _{iss}	-	1032	-		$V_{DS} = 25V, V_{GS} = 0V,$ f = 1.0MHz
Output capacitance	Coss	-	1192	-	~ F	
Reverse transfer capacitance	C _{rss}	-	54.8	-	pF	
Effective output capacitance energy related ⁽⁴⁾	C _{o(er)}	-	29.3	-		$V_{DS} = 0V \text{ to } 520V, V_{GS} = 0V, f = 1.0MHz$
Turn on delay time	t _{d(on)}	-	23.5	1	ns	$V_{GS} = 10V, R_G = 25\Omega,$ $V_{DS} = 325V, I_D = 13.8A$
Rise time	t _r	-	59	-		
Turn off delay time	$t_{d(off)}$	-	151	1		
Fall time	t _f	-	52	-		
Total gate charge	Q_g	-	27.8	-		
Gate – source charge	Q_{gs}	-	9.9	-	nC	$V_{GS} = 10V, V_{DS} = 520V,$ $I_{D} = 13.8A$
Gate – drain charge	Q_{gd}	-	7.1	-		
Gate resistance	R _G	-	21	-	Ω	V _{GS} = 0V, f = 1.0MHz

⁴⁾ $C_{\text{o(er)}}$ is a capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0V to 80% $V_{(BR)DSS}$

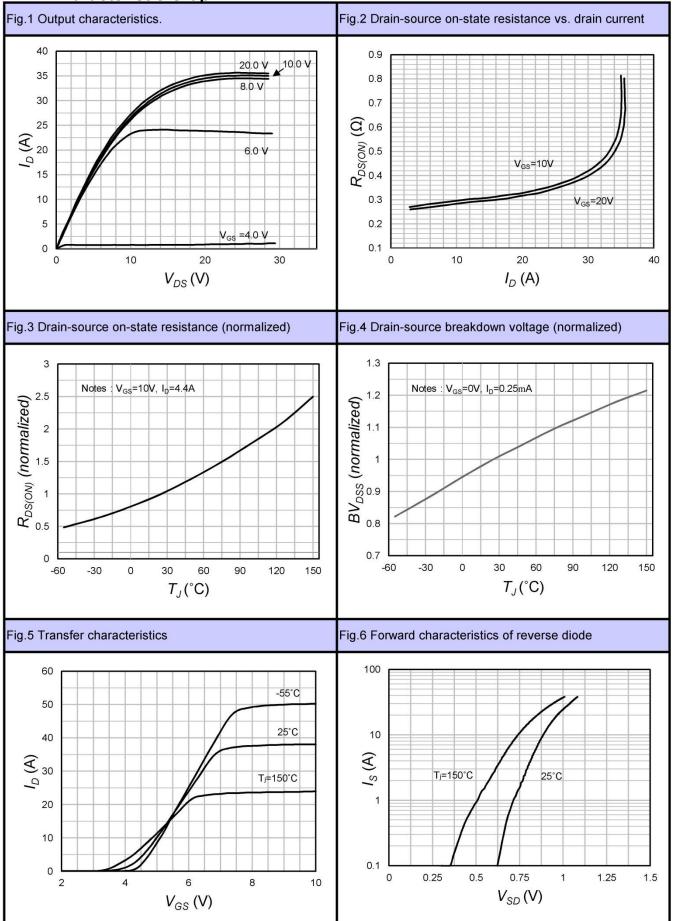


■ Reverse Diode Characteristics (T_c=25°C unless otherwise specified)

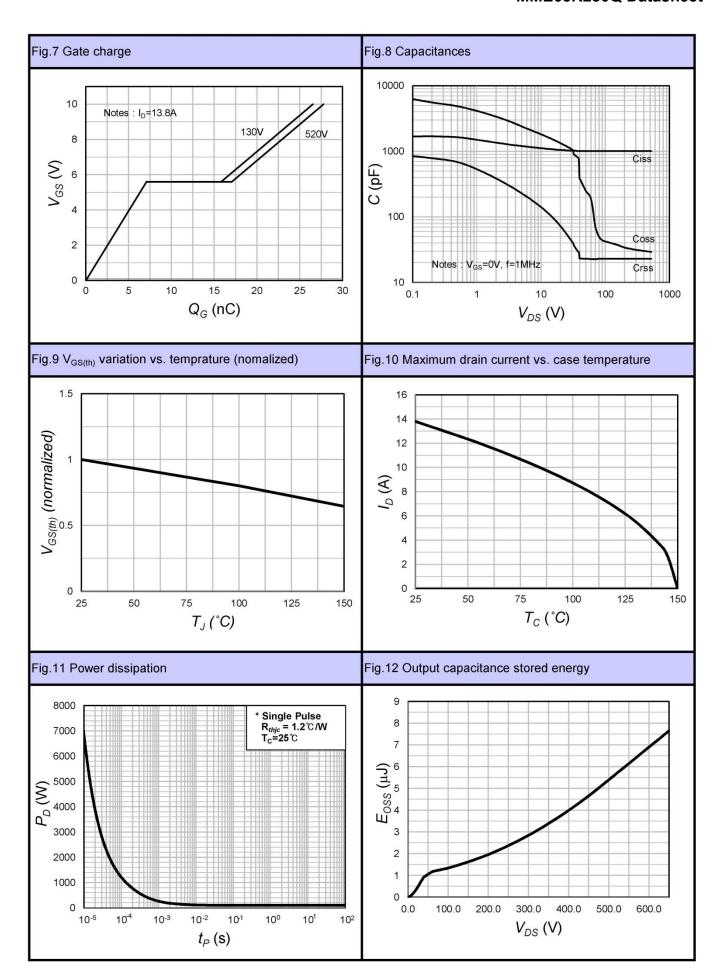
Parameter	Symbol	Min.	Тур.	Max.	Unit	Test Condition
Continuous diode forward current	Is	-	-	13.8	Α	
Diode forward voltage	V_{SD}	-	-	1.4	V	I _S = 13.8A, V _{GS} = 0V
Reverse recovery time	t _{rr}	-	377	-	ns	I _S = 13.8A di/dt = 100A/μs V _{DD} = 100V
Reverse recovery charge	Qrr	-	5.2	-	uC	
Reverse recovery current	I _{rrm}	-	27.6	-	Α	



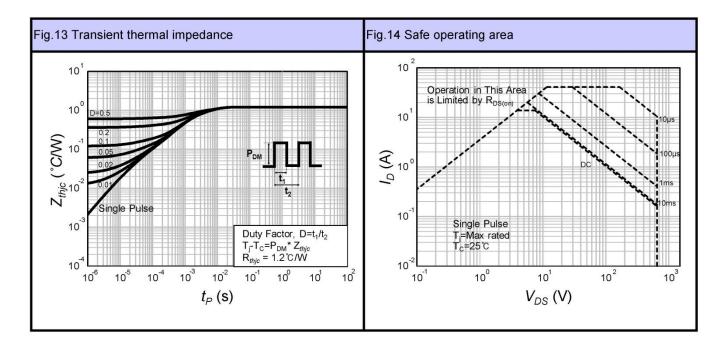
■ Characteristic Graph













■ Test Circuit

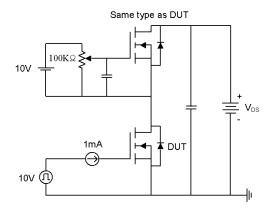


Fig15-1. Gate charge measurement circuit

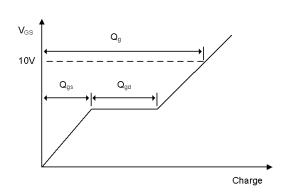


Fig15-2. Gate charge waveform

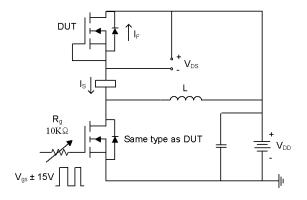


Fig16-1. Diode reverse recovery test circuit

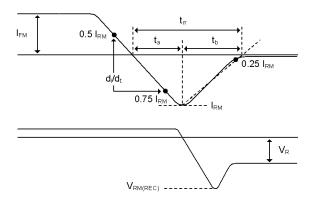


Fig16-2. Diode reverse recovery test waveform

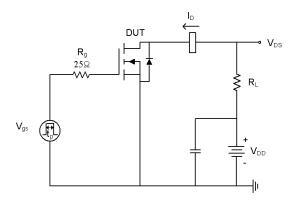


Fig17-1. Switching time test circuit for resistive load

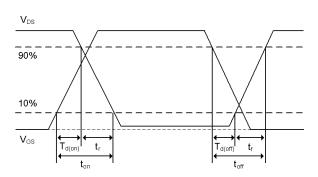


Fig17-2. Switching time waveform

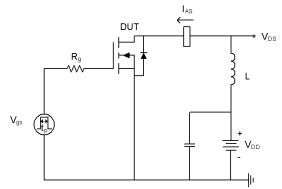


Fig18-1. Unclamped inductive load test circuit

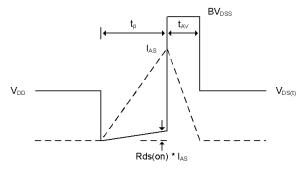
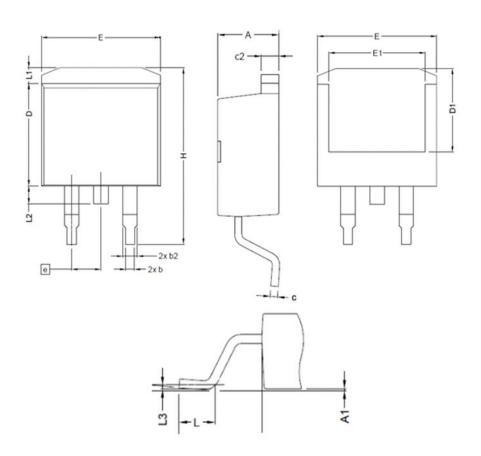


Fig18-2. Unclamped inductive waveform



■ Physical Dimension

TO-263



[Unit:mm]

C	Millimeters(mm)					
Symbol	Min	Max				
А	4.064	4.826				
A1	-	0.254				
b	0.508	0.99				
b2	1.140	1.778				
С	0.310	0.736				
c2	1.140	1.650				
D	8.382	9.652				
D1	6.6	-				
E	9.652	10.668				
E1	6.223	-				
е	BSC	2.54				
Н	14.605	15.875				
L	1.778	2.794				
L1	-	1.676				
L2	-	1.778				
L3	BSC 0.254					

Note: Package body size, length and width do not include mold flash, protrusions and gate burrs.





DISCLAIMER:

The Products are not designed for use in hostile environments, including, without limitation, aircraft, nuclear power generation, medical appliances, and devices or systems in which malfunction of any Product can reasonably be expected to result in a personal injury. Seller's customers using or selling Seller's products for use in such applications do so at their own risk and agree to fully defend and indemnify Seller.

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